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Hydrothermal–galvanic couple synthesis of directionally oriented BaTiO₃ thin films on TiN-coated substrates[☆]

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ABSTRACT

BaTiO₃ films were synthesized on TiN-coated Si substrate below 100 °C by a hydrothermal–galvanic couple technique in barium contained alkaline solutions. X-ray diffraction and electron backscatter diffraction results show that the BaTiO₃ thin films were directionally oriented grown on the TiN/Si substrates, i.e., (111) BaTiO₃ over (111) TiN. The surface morphologies revealed that BaTiO₃ nucleated and grew over the TiN surface with a single layer. From kinetic analyses, the growth rates of BaTiO₃ films prepared by the hydrothermal–galvanic couple technique were faster than a hydrothermal method. The galvanic effects were confirmed by investigating the induced currents and energies. The galvanic currents were generated and controlled by both the dissolution of TiN and the formation of BaTiO₃. The output electric energies increased rapidly with the reaction time and leveled off at the full coverage of BaTiO₃.

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1. Introduction

Barium titanate (BaTiO₃) is one of the most important electroceramic materials due to its superior dielectric and ferroelectric properties [1,2]. BaTiO₃ films have been widely used in cutting-edge applications, such as dynamic random access memory, chemical sensors, and multilayer chip capacitors [3–5]. In the literature, various techniques have been reported for the synthesis of BaTiO₃ films including pulsed laser deposition [6], ion-beam sputtering technique [7], sol–gel process [8], hydrothermal [9–16], and hydrothermal–electrochemical methods [17–25]. Most of the techniques require temperatures higher than 500 °C to enhance crystallinity of the films except hydrothermal and hydrothermal–electrochemical methods which may bring the temperature down near or below 100 °C [13–19]. Fig. 1 summarizes the lowest reaction temperature of the hydrothermal and hydrothermal–electrochemical synthesis of BaTiO₃ films, reported from the literature including our previous work on the hydrothermal–galvanic couple (HT–GC) and hydrothermal (HT) synthesis of BaTiO₃ films [26–28]. This technique can reduce the reaction temperature down even below 55 °C.

As reported in our previous work, synthesis of BaTiO₃ films by a HT–GC technique may significantly enhance the growth rates of the films. During the galvanic couple setup, no external power supply was required but the growth of BaTiO₃ films could be enhanced significantly by the induced current/voltage. Moreover, unlike the conventionally used bulk Ti, Ti/Si, or TiO₂ substrates [29–34], TiN/Si substrates were used during the synthesis of BaTiO₃. Because of the low resistivity and highly preferred orientation of TiN, BaTiO₃ films were found to grow directionally over the TiN/Si substrates [26]. Nevertheless, the growth kinetics of synthesizing the films by the HT–GC technique has not yet been investigated. The galvanic effects during the synthesis of the films have not yet been explored, either.

Thus, this work was aimed to investigate the growth kinetics of BaTiO₃ films synthesized by the HT–GC method and then to compare the results with those made by the sole hydrothermal method. The effect of the galvanic couple setup on the growth of the films has also been explored.

2. Experiment

TiN films were prepared on n-type (100) silicon substrates by DC reactive sputtering, as reported in our previous work [28]. The deposition time was 3 min and the resulting thickness of TiN was 400 nm. The resistivity of the obtained TiN was in the range of 310–350 μΩ cm.

In the HT–GC synthesis, the reaction solution was a mixture of 0.5 M Ba(CH₃COO)₂ (99.5%, J.T. Baker, U.S.A) and 2 M NaOH (99%, Riedel-de Haën, Germany) alkaline solutions. The reaction temperatures were kept below 100 °C and hence, no autoclave was required. As for the

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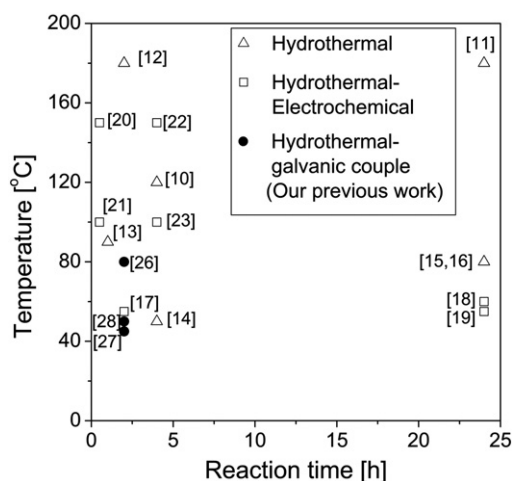


Fig. 1. The lowest reaction temperatures of the hydrothermal and hydrothermal-electrochemical synthesis of BaTiO₃ films, reported from the literature including our previous work [26–28].

galvanic couple setup, the working electrode was the TiN/Si specimens and the counter electrode was Pt while the two electrodes were directly connected without applying any external power sources.

Crystalline phases of the films were determined by X-ray diffraction (XRD) (MPX3, Mac Science, Japan) operated at 40 kV and 30 mA with a Cu K α excitation source ($\lambda_{\text{Cu,K}\alpha} = 0.1542$ nm). Surface and cross-sectional morphologies of the films were investigated by field-emission scanning electron microscopy (FE-SEM) (JSM-6700 F, JEOL, Japan) operated at 3 kV to minimize the charging effect. Electron backscatter diffraction (EBSD) (JSM-7001 F, JEOL, Japan) was also conducted to examine the grain orientations of the obtained films. The growth kinetics was evaluated by analyzing the coverage of BaTiO₃ over the TiN films as a function of the reaction time. The coverage of BaTiO₃ was calculated by averaging five selected areas in the SEM micrographs taken from each specimen.

3. Results and discussion

3.1. Crystallinity

Fig. 2 shows the X-ray diffraction patterns of the as-deposited films and those after the (a) HT–GC and (b) HT syntheses at various temperatures for 2 h. The as-deposited films were rock-salt structured TiN (JCPDS 38-1420) [35] with a highly (111) preferred orientation. As shown in the figure, the crystalline cubic BaTiO₃ (JCPDS 31-0174) [35] phase was present after the syntheses at the temperatures above 50 °C and grew directionally over TiN-coated substrates. It is noteworthy that the relative intensities of BaTiO₃ obtained in this referenced HT synthesis were slightly different from those reported in our previous work [28]. This is mainly due to the different batch of the specimens, which doesn't affect the conclusions deduced from this work. The directionally oriented growth of BaTiO₃ during the HT–GC synthesis, i.e., (111) BaTiO₃ over (111) TiN, is also very similar to that for the HT synthesis.

3.2. Morphology

In Fig. 3, the as-deposited TiN seeding layer revealed a nano-grained structure and BaTiO₃ started to nucleate and grow over the seeding layer for both the (a) HT–GC and (b) HT synthesis. As shown, only a few BaTiO₃ particles grew over the TiN surface at 45 °C. The coverage of BaTiO₃ increased rapidly with the reaction temperature ranging from 45 °C to 60 °C. At reaction temperatures higher than 60 °C, the BaTiO₃ particles almost covered the whole TiN surface. The trend is

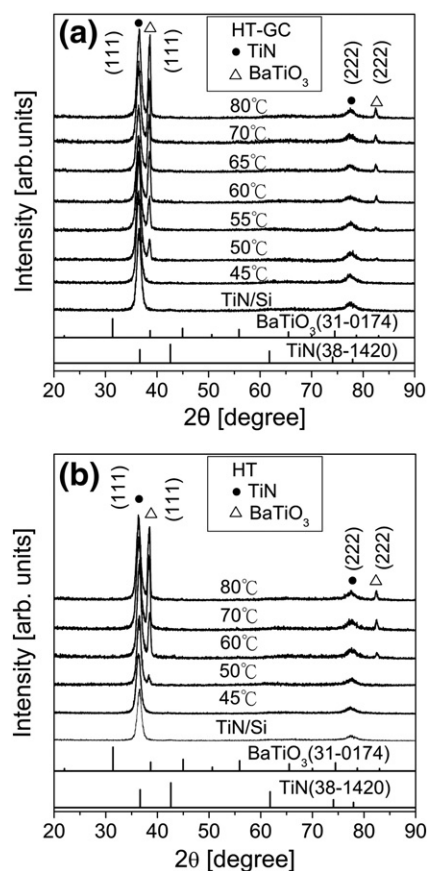


Fig. 2. X-ray diffraction patterns of BaTiO₃ over TiN/Si synthesized by the (a) HT–GC and (b) HT methods at various temperatures for 2 h.

similar to those synthesized by both the HT–GC and HT methods. At a fixed reaction temperature, the amount of BaTiO₃ particles obtained by using the HT–GC was obviously larger than that synthesized by the HT method in the temperature range of 45 °C–60 °C. It clearly indicates that the galvanic couple setup can facilitate the growth of BaTiO₃. Here, it also demonstrates that the HT–GC technique can be used to produce BaTiO₃ films at lower reaction temperature (<50 °C), compared to the HT and hydrothermal–electrochemical methods, as revealed in Fig. 1.

The cross-sectional view of the BaTiO₃ films obtained by the HT–GC method is given in Fig. 4. As-deposited TiN exhibited a characteristic columnar structure. The TiN films were then slightly consumed after the syntheses at various temperatures for 2 h. The BaTiO₃ particles were produced, yielding a single layer over the TiN film surface. That's why the coverage instead of thickness was used for analyzing the kinetics. It is noteworthy that the interface between TiN and formed BaTiO₃ was rather smooth. Moreover, porosity existed in the BaTiO₃ films. The porosity of the BaTiO₃ films can be calculated based on the theoretical estimation [36] and experimental observations. Taking the synthesis at 80 °C shown in Fig. 4 as an example, the consumed thickness of TiN was 19 ± 1 nm that should yield 64 ± 1 nm (3.4 times) of a fully dense BaTiO₃ film. However, the experimentally observed thickness of BaTiO₃ was 71 ± 1 nm. That means the porosity existing in the BaTiO₃ film might be about 10%. The discrepancy between the estimation and the observation may also stem from the densities used in the calculation since the bulk and film densities are possibly different and only the former value is available at the moment.

As mentioned earlier in the XRD analysis, directionally-oriented growth of the BaTiO₃ films was observed over the TiN seeding layer that exhibited a strong preferred orientation. To further examine the oriented growth, EBSD was also performed over different grains

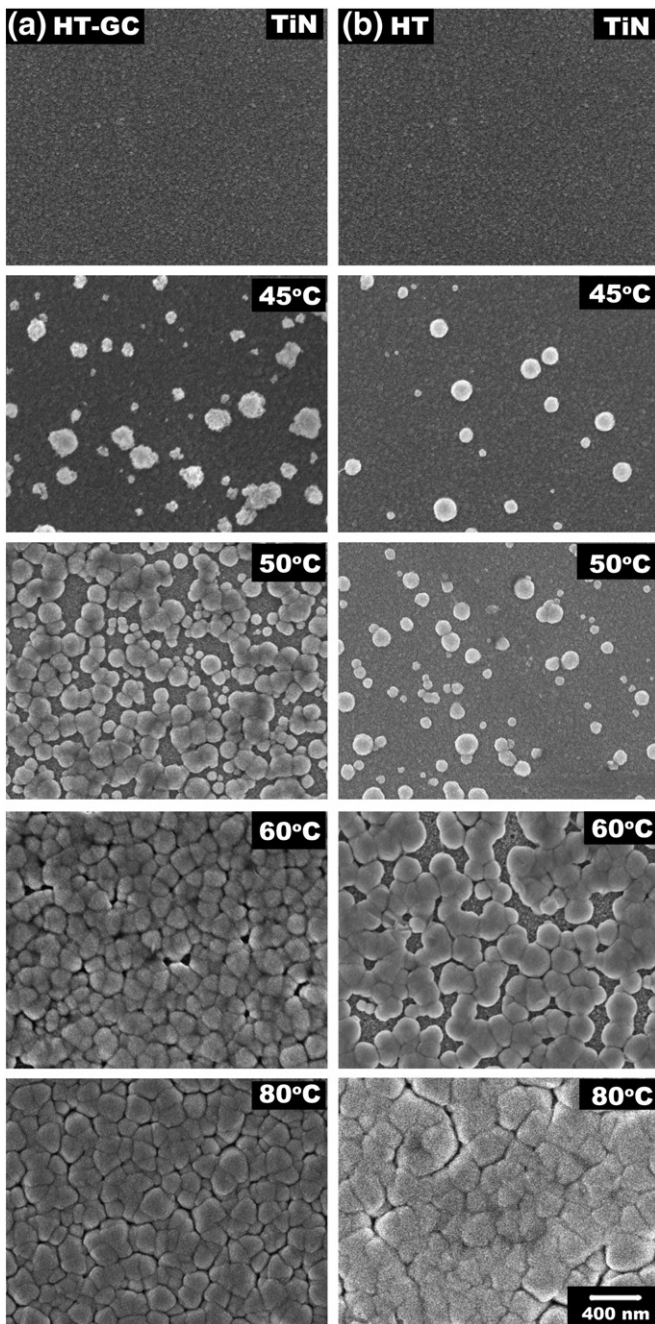


Fig. 3. FE-SEM micrographs of surface morphology of BaTiO₃ synthesized by the (a) HT-GC and (b) HT methods at various temperatures for 2 h.

of the obtained films. A typical set of micrographs is given in Fig. 5. Fig. 5a revealed the grains of the films selected for the electron backscatter diffraction.

From the obtained Kikuchi pattern of each BaTiO₃ grain, as shown in Fig. 5b, the pole figure of the different grains could be acquired, as sketched in Fig. 5c. The central point represented the [111] orientation. The other three points referred to the family of the {111} orientations. All the grains show similar results, which indicated the [111] preferred growth direction. This verified the directionally oriented growth of the oxide films, i.e., (111) BaTiO₃/(111) TiN. This indicates that the highly oriented TiN films can be used to design different directionally-oriented BaTiO₃ films by this synthesizing method. That can be also extended to other similar perovskite oxide/conductive nitride systems.

3.3. Growth kinetics

To more accurately quantify the growth kinetics of BaTiO₃ over the TiN seeding layer, the coverage of BaTiO₃, y , was fitted to a modified Avrami-Erofe'ev equation [37–40], as given below:

$$y = 1 - \exp[-k(t-t_0)]^n \quad (1)$$

where k is the rate constant, t is the reaction time, t_0 is the incubation time before the formation of BaTiO₃, and n is the time exponent constant. Since the coverage of BaTiO₃ seemed to proceed by the increase in numbers of nuclei rather than their growth, as shown in Fig. 3, such nucleation and growth behavior of BaTiO₃ has not been reported in the literature. Nevertheless, the Avrami-Erofe'ev or modified equation has been applied to a wide range of studies, including time-dependence of the nucleation [41], crystallization and phase transformation in glasses and alloys, metal hydrogenation reactions [42], and anion exchange reactions in layered materials [43]. Hence, a modified Avrami-Erofe'ev equation has been tried to analyze the growth kinetics. It turns out that kinetic behavior of the HT-GC and HT syntheses can be fitted rather well by the equation, as shown in Fig. 6. It indicates that the growth of the films increased quickly with the reaction time and followed the kinetic model. At fixed reaction time and reaction temperature, the coverage of BaTiO₃ synthesized by the HT-GC method was much larger than that prepared by HT synthesis. The growth did not occur until the reaction time exceeded the incubation time, t_0 . The incubation time decreased rapidly with the temperature. As the reaction temperature increased from 50 °C to 80 °C, the incubation time was reduced from 1800 s to 50 s, for the HT-GC synthesis. Apparently higher temperatures can provide energy to overcome the potential barrier and activate the formation of BaTiO₃ particles. Moreover, the galvanic couple setup can also aid significantly the growth of BaTiO₃.

Beside the variation of the incubation time t_0 with the reaction temperatures, as sketched in Fig. 7a, other fitting parameters including n

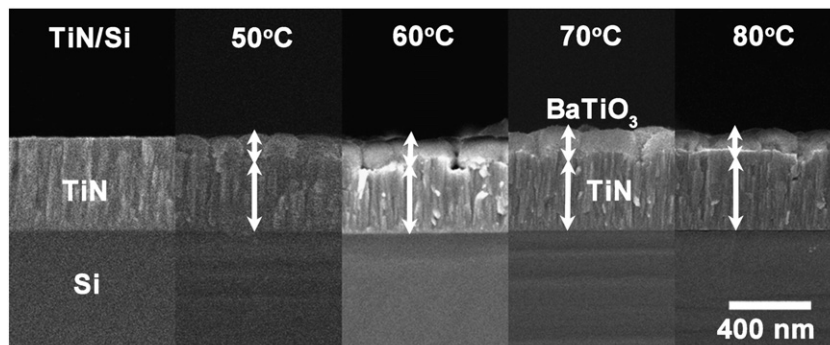


Fig. 4. Cross-sectional view of BaTiO₃ over TiN/Si synthesized by the HT-GC method at various temperatures for 2 h.

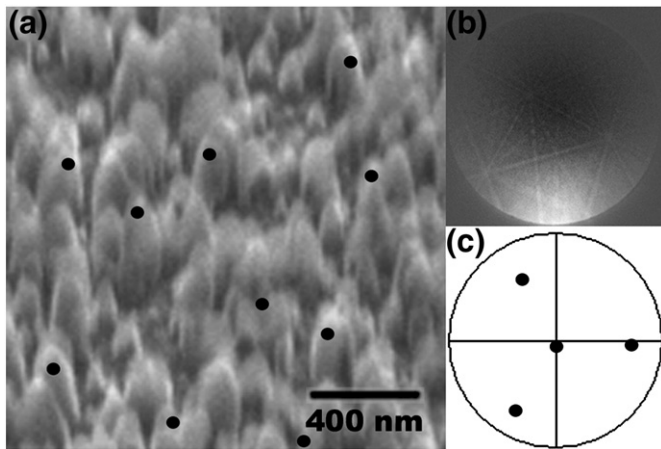


Fig. 5. (a) The tiled (70°) FE-SEM micrographs of BaTiO₃ after the HT-GC synthesis at 80 °C for 10 min. (b) The typical Kikuchi pattern of a selected grain designated in (a). (c) The pole figure of the selected grains indicating the [111] growth direction.

and k are shown in Fig. 7b and c. The value of n is associated with the reaction mechanism, which has been discussed in the literatures [34]. As shown in Fig. 7b, the n -value was close to 1 during the HT synthesis and was consistent with our previous work [28], which implies that the growth of films was controlled by phase boundary reactions [34]. As for the HT-GC synthesis, the n -value was also near 1 in the range of 60 °C–70 °C. Nevertheless, the n -value was higher than 1 at the reaction temperatures below 60 °C, implying that the HT-GC synthesis

might be controlled by more complex reactions. Fig. 7c shows the reaction constant k in logarithm scale against the temperature. The k -values for the HT-GC synthesis were larger than those for the HT synthesis and the difference increased with the temperature, which is apparently due to the galvanic effect during the HT-GC synthesis. This indicates that the galvanic effect during the HT-GC synthesis was more and more evident at higher temperatures and could then enhance the reaction.

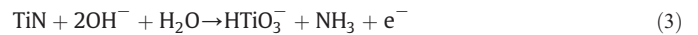
The activation energy of forming BaTiO₃ could be determined by fitting the rate constant to the Arrhenius-type equation.

$$k = k_0 \exp\left(-\frac{Q}{RT}\right) \quad (2)$$

where k_0 is the pre-exponent constant, Q is the activation energy, R is the gas constant, and T is the reaction temperature. From the fitting results, the calculated activation energy for the HT synthesis was $55 \pm 4 \text{ kJ mol}^{-1}$ in the temperature range of 60 °C–80 °C, which is consistent with that reported in our previous work [28]. Nevertheless, $\ln k$ vs. $1/T$ for the HT-GC synthesis shows a nonlinear behavior. It indicates that the HT-GC technique is governed by multiple formation mechanisms including at least hydrothermal reaction and galvanic-aided formation. To explore the galvanic couple effects during the HT-GC synthesis, the induced currents and corresponding electric energies were investigated and reported in the later section.

3.4. Galvanic couple effect

It is generally recognized that HT synthesis of BaTiO₃ is governed by a dissolution–precipitation mechanism [44–47]. It has been reported that TiN would be oxidized in highly concentrated alkaline solutions [48]:



Barium ions could then react with HTiO₃[−] ions to form barium titanate,



Since TiN exhibits a certain degree of ionic bonding in addition to covalent bonding, it may be much easier to dissolve into alkaline solutions than Ti to yield BaTiO₃ films, as described in our previous work for the low-temperature HT synthesis [28]. As given in Eq. (3), more enhanced dissolution reactions at higher reaction temperatures would produce more electric charges and then enhance the galvanic effects. Nucleation of BaTiO₃ occurred via the dissolution–precipitation mechanism. TiN firstly dissolved in alkaline solutions to form HTiO₃[−] ions and then reacted with Ba²⁺ ions to BaTiO₃. Because the TiN films exhibited nanogranular and columnar structure, as shown in Fig. 4, the dissolution of TiN in alkaline solution might occur at the grain boundaries which could accumulate high concentration of HTiO₃[−] ions. This may yield inhomogeneous nucleation of BaTiO₃.

In an electrochemical system, the current is determined by the reaction rates at the electrodes. As the electrochemical reaction occurs at the electrode–electrolyte interface, it is called heterogeneous reaction and the reaction rate depends on various factors, such as mass transfer to the electrode and electron transfer at the electrode surface. The reaction rate associated with the current density can be expressed by the following equation [49]:

$$\text{Rate} (\text{mols}^{-1} \text{cm}^{-2}) = \frac{j}{nF} \quad (5)$$

with j the current density, n the stoichiometric number of electrons in the electrode reaction, and F the Faraday constant. As shown in Fig. 8, the in-situ measured (a) current densities and (b) corresponding electric energies are plotted against the reaction time at various synthesizing temperatures. The competitive reactions of both dissolution of

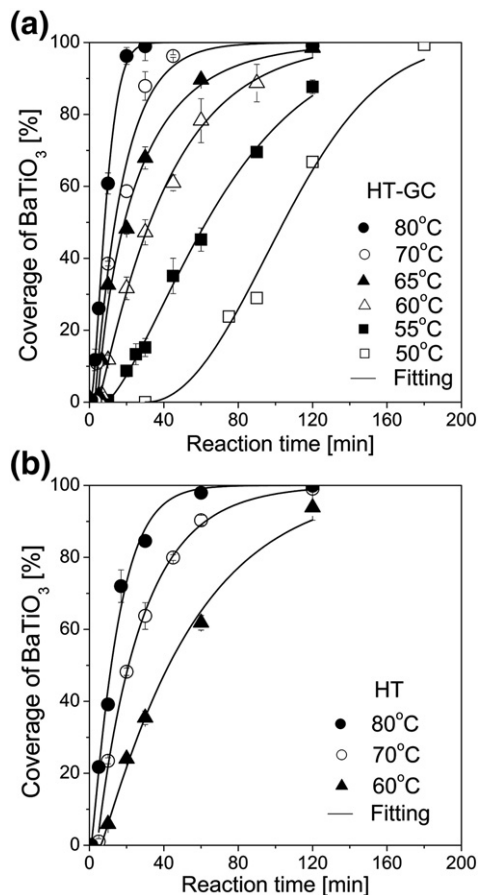


Fig. 6. The coverage of BaTiO₃ synthesized by the (a) HT-GC and (b) HT methods as a function of the reaction time at various reaction temperatures. The solid lines are the fitting curves by using a modified Avrami–Erofe'ev equation.

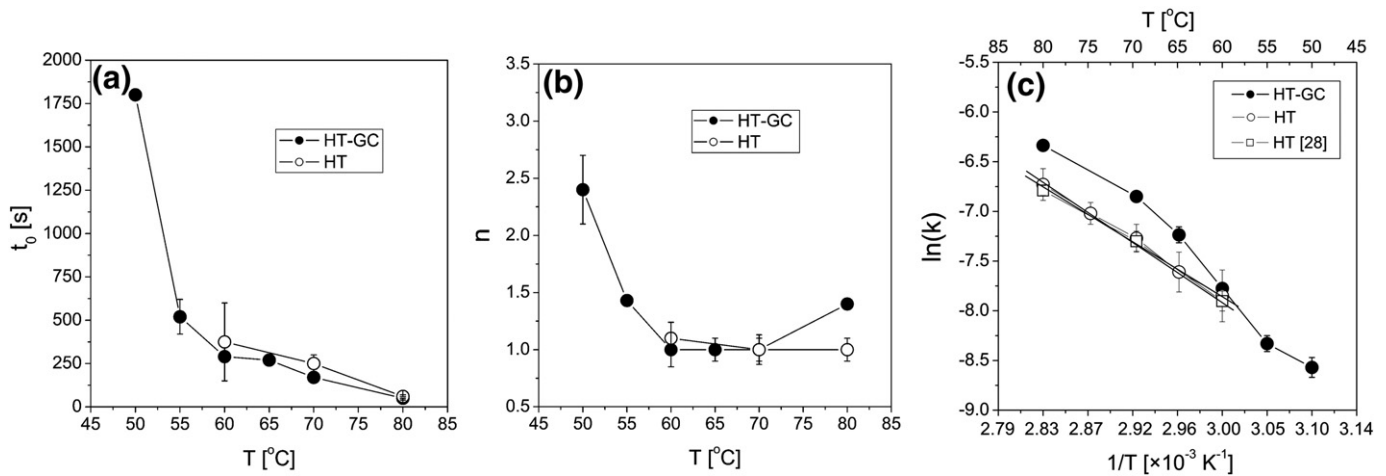


Fig. 7. (a) The incubation time t_0 , (b) the time exponent constant n , versus the reaction temperature and (c) the logarithm k vs. $1/T$ for both the HT and HT-GC syntheses.

TiN and the formation of BaTiO_3 yield a maximum current density at each reaction temperature. As shown in Fig. 8a, the maximum current density increased with reaction temperatures. Higher reaction temperatures apparently enhance both reactions, causing higher maximum current density. The galvanic currents can be divided into three regimes for a fixed reaction temperature. Initially, the galvanic currents abruptly decreased to a minimum. Subsequently, the currents increased rapidly to a maximum and finally returned to a background value. It is possible that at the beginning TiN films dissolve into alkaline solution and produce HTiO_3^- ions accumulated on the TiN surface, which may hinder the dissolution reaction and cause the current decrease. This

time period at which BaTiO_3 has not yet been formed can be referred to the incubation time, as mentioned earlier. Next, the significant galvanic current increase is mainly due to the reactions of Ba^{2+} ions with HTiO_3^- ions, leading to the formation of BaTiO_3 and further dissolution of TiN. The latter reaction results in the current increase. In our case, the dissolution of TiN and the precipitation of BaTiO_3 occurred concurrently at the working electrode, as given in Eqs. (3) and (4). Current density was enhanced by the dissolution of TiN while was suppressed by the precipitation of BaTiO_3 . It is noteworthy that the maximum current density occurs at the time when half of the TiN surface was covered by BaTiO_3 . Subsequently, the produced BaTiO_3 particles gradually cover over the TiN film surface and reduce the effective reaction area of the TiN films, which would hinder the dissolution of TiN and then slowly suppressed the galvanic current. After reaching full coverage of the BaTiO_3 particles, the galvanic effect is ceased and the galvanic current then returns to the background value. Since no external voltages or currents were applied to the system, the spontaneous currents clearly stem from the galvanic couple effect.

During the galvanic reactions chemical energy can be transformed into electric energy. The output electric energy, evaluated from measured currents and voltages, as well as reaction time, is also plotted against the reaction time at various temperatures, as sketched in Fig. 8b. It shows that the electric energy increased rapidly with the reaction time and then reached a constant value that indicates the TiN surface was fully covered by BaTiO_3 and the galvanic reaction was self-terminated. The maximum generated electric energy density was about $1.61 \pm 0.05 \text{ mJ/cm}^2$, which is almost independent of the reaction temperature. It is also revealed in the figure that the maximum electric energy density can be reached much faster at higher reaction temperatures, since the galvanic reactions are more enhanced at higher temperatures.

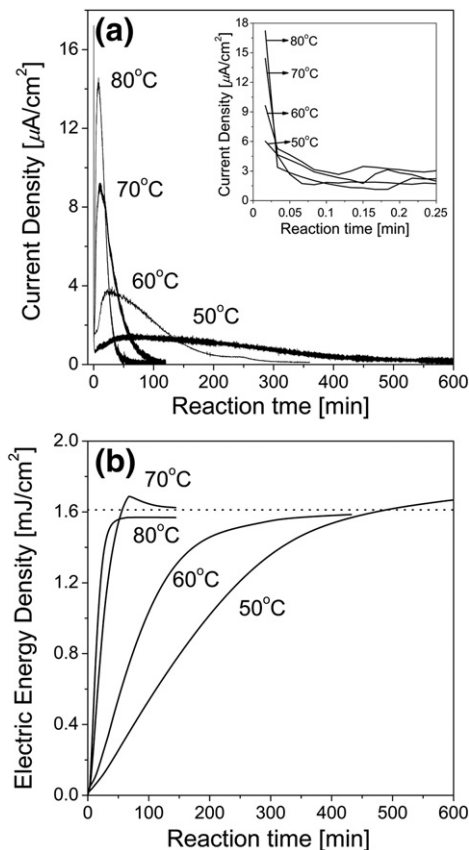


Fig. 8. (a) Current density and (b) electric energy density vs. reaction time at various temperatures during the HT-GC synthesis.

4. Conclusions

Directionally oriented (111) cubic BaTiO_3 films have been produced on the highly oriented (111) TiN layer by the HT-GC method above 45°C while below 100°C . The growth rates of BaTiO_3 synthesized by the HT-GC method are much faster than those prepared by the HT technique from the growth kinetic analysis. Compared to the HT methods, the HT-GC synthesis is apparently governed by more complex reaction mechanisms including the galvanic reactions. The galvanic current density was generated by the dissolution of TiN in alkaline solution and was tailored by the formation of BaTiO_3 over the TiN layer. The maximum galvanic current increased with the reaction temperature while the maximum current occurred at the time when

half of the TiN surface was covered by BaTiO₃. The output electric energy increased rapidly with the reaction time and finally leveled off at the full coverage of BaTiO₃. The HT–GC method with the aide of galvanic couple effects has great potentials in synthesizing many oxide materials.

Acknowledgments

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